## Supporting Information

## Polarity Flipping in Iso-Type Heterojunction (p-

## SnS/p-Si) to Enable a Broadband Wavelength

## Selective Energy-Efficient Photodetector

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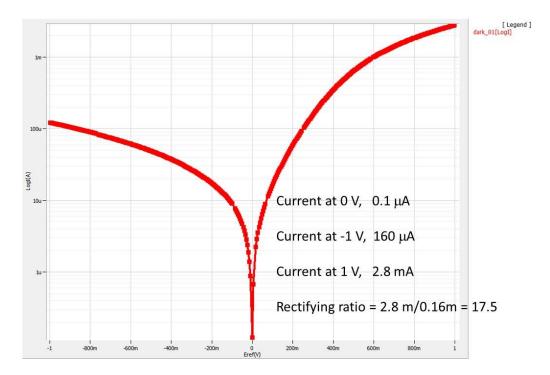


Fig. S1 Dark I-V characteristics of p-p isotype heterojunction (p-Si/p-SnS) device.

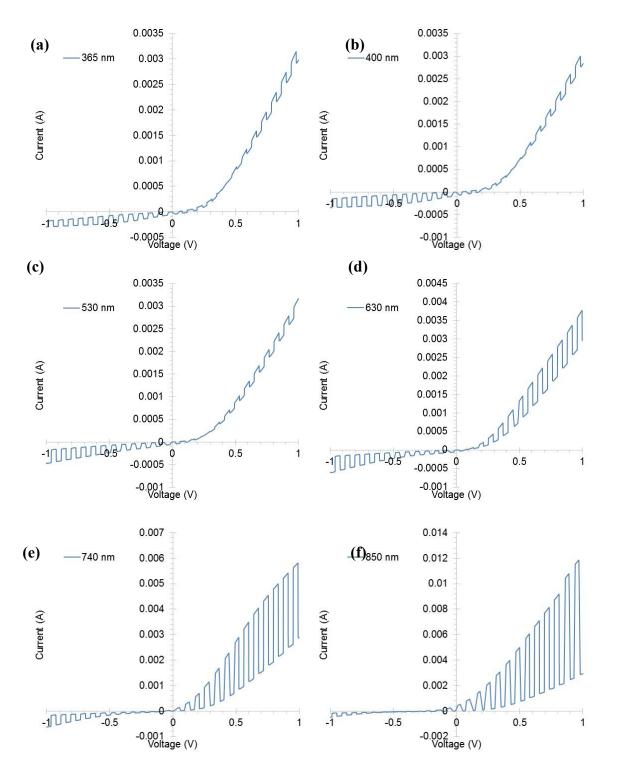
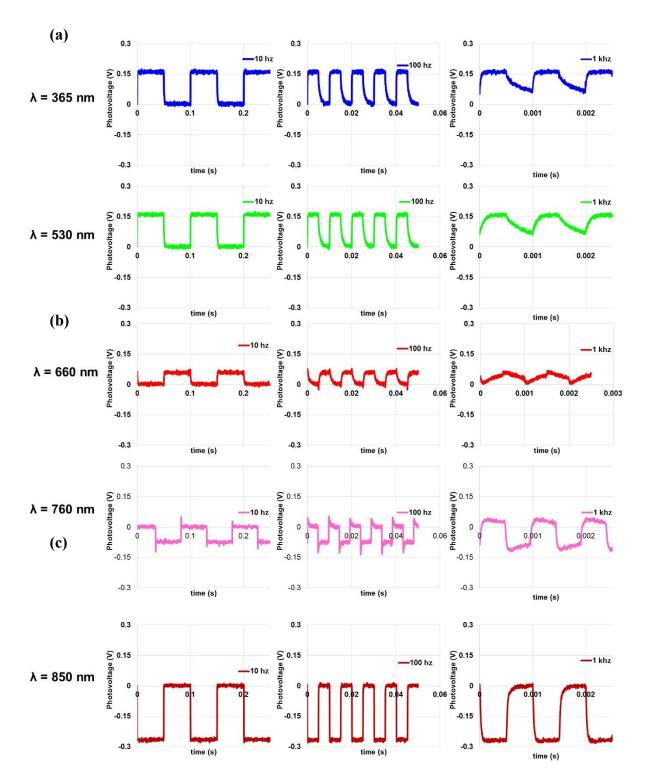


Fig. S2 Current-voltage characteristics of the device under the pulsed light illumination, (a)  $\lambda = 365$  nm, (b)  $\lambda = 400$  nm, (c)  $\lambda = 530$  nm, (d)  $\lambda = 630$  nm, (e)  $\lambda = 740$  nm, and (f)  $\lambda = 850$  nm. Scan direction is -1 V to 1 V, scan rate is 100 mV s<sup>-1</sup>, scan interval is 1 mV, and light pulse frequency 1.3 Hz.



**Fig. S3** Transient photovoltage plots of the device under various pulsed frequency (10 Hz, 100 Hz and 1 kHz) of light illumination, (a)  $\lambda = 365$  nm, (b)  $\lambda = 530$  nm, (c)  $\lambda = 660$  nm, and (d)  $\lambda = 760$  nm, and (e)  $\lambda = 850$  nm.

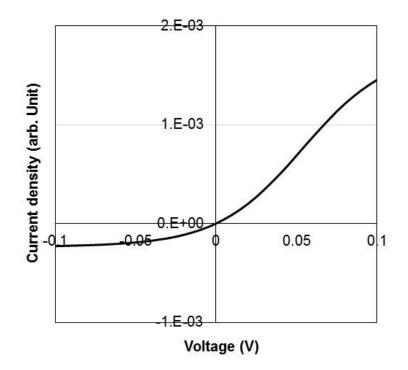


Fig. S4 Simulated J-V characteristic of the device under dark condition.

# of scan	Bulk Con. (cm-3)	Resistivity ( $\Omega$ cm)	Mobility (cm <sup>2</sup> V <sup>-1</sup> s <sup>-1</sup> )
1	$1.84  imes 10^{17}$	65.08	5.19
2	$1.40  imes 10^{17}$	65.21	6.83
3	$1.57\times10^{17}$	65.24	6.07
Average	$1.60  imes 10^{17}$	65.18	6.03

Table S1. Hall measurement of the 100 nm-thick SnS film.

**Table S2.** Responsivity (R\*) and detectivity (D\*) for wavelength of 400 nm and 800 nm. The photo-induced  $R_{ph}^*$  and  $D_{ph}^*$  values calculated using the relation  $R_{ph}^* = |J_{ph} - J_{dark}|/P_{in}$  and  $D_{ph}^* = R_{ph}^*/\sqrt{2qJ_{dark}}$ , respectively, where  $J_{ph}$  is the photo current density,  $J_{dark}$  is the dark current density,  $P_{in}$  is the incident light intensity, and q is electron charge. Considering the pyroelectric effect,  $R_{ph+py}^*$  and  $D_{ph+py}^*$  can be formed by  $R_{ph+py}^* = |J_{ph+py} - J_{dark}|/P_{in}$  and  $D_{ph+py}^* = R_{ph+py}^*/\sqrt{2qJ_{dark}}$ .

Wavelength (nm)	Light intensity (mW cm <sup>-2</sup> )	Photo-induced		Photo+Pyro-induced	
		R* <sub>ph</sub> (mA W <sup>-1</sup> )	D* <sub>ph</sub> (Jones)	R* <sub>ph+py</sub> (mA W <sup>-1</sup> )	D* <sub>ph+py</sub> (Jones)
400 nm	10	34.45	$1.97 \times 10^{13}$	66.25	$3.79 \times 10^{13}$
800 nm	150	11.44	$5.93 \times 10^{12}$	14.80	$7.68 \times 10^{12}$